## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | ALLEN ET AL. | Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0225333 A1	11-2004	Greatbatch et al.	607/034
*	В	US-6,437,308 B1	08-2002	Koh, Young-Sik	250/214R
*	С	US-6,373,326 B1	04-2002	Tomari, Nobuhiro	327/536
*	D	US-6,348,806 B1	02-2002	Okandan et al.	324/763
*	E	US-6,118,293	09-2000	Manhaeve et al.	324/765
*	F	US-4,797,608	01-1989	White, Randall A.	324/96
*	G	US-4,713,819	12-1987	Yoshikawa, Shozi	372/9
*	Н	US-4,020,366	04-1977	Garner et al.	327/114
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-	<del>, , , , , , , , , , , , , , , , , , , </del>		

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р				·	
	σ					
	R					
	S					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.